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3501-1007

PATENTS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#5

In re application of

Jussi TENHUNEN et al.

Confirmation No. Unassigned

Serial No. 10/089,161

Group Unassigned

Filed March 27, 2002

Examiner Unassigned

SPECTROMETER AND METHOD FOR MEASURING OPTICAL SPECTRUM

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents

Washington, D.C. 20231

Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the following documents, copies of which are attached to this statement, are made of record on the enclosed sheet.

A concise explanation of the relevance of the items listed on page 1 of the attached PTO Form 1449 is that we are advised by our client that these references were discovered during any searches they or their client had made, or that they were considered in the preparation of the application:

In addition, the remaining documents, copies of which are attached to this statement, are also made of record on the enclosed sheet.

A concise explanation of the relevance of these latter items listed on page 2 of the attached PTO Form 1449 is that we are advised by our client that these references were cited in the International Search Report in the corresponding

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S.N. 10/089,161

International application Serial No. PCT/FI00/00824, filed September 27, 2000, and by the Finnish Patent Office in the corresponding Finnish Application Serial No. 19992092, filed September 29, 1999. Copies of the International Search Report and Finnish Official Action in which they were cited are attached hereto.

Respectfully submitted,

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By



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June 14, 2002

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.
3501-1007

SERIAL NO.
10/089,161

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

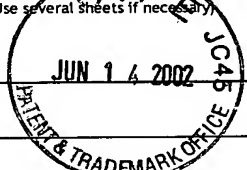
(Use several sheets if necessary)

37 CFR 1.98(b)

APPLICANT
Jussi TENHUNEN et al.

FILING DATE
March 27, 2002

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Unassigned



U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,504,575	04/96	Stafford			
	AB	4,615,619	10/86	Fateley			
	AC	3,859,515	01/75	Radcliffe			
	AD						

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
	AI						
	AJ						

OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)

	AT	James D. Batchelor et al., "Development of a Digital Micromirror Spectrometer for Analytical Atomic Spectrometry," <u>Analytical Chemistry</u> , V. 70, 1998, pp. 4907-4914.
	AU	P. Krippner et al., "Microspectrometer for the Infrared Range," <u>SPIE</u> , V. 2783, 1996, pp. 277-282.
	AV	P. Rai-Choudhury, ed., <u>Handbook of Microlithography, Micromachining, and Microfabrication</u> , Vol. 2: Micromachining and Microfabrication, 1997, IEE, pp. 236-376.
	AX	Martin Harwit et al., <u>Hadamard Transform Optics</u> , Academic Press, 1979, pp. v-ix.
	AY	J. A. Decker, Jr., "Experimental Realization of the Multiplex Advantage with a Hadamard-Transform Spectrometer," <u>Applied Optics</u> , V. 10, 1971, pp. 510-514.

EXAMINER

DATE CONSIDERED

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,631,735	05/97	Nagai			
	AB	4,790,654	12/88	Clarke			
	AC	4,790,652	12/88	Unéus et al.			
	AD	5,856,871	01/99	Cabib et al.			
	AE	4,448,529	05/84	Krause			
	AF						

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
	AI	0 550 076 A1	07/93	EP			
	AJ	0 548 830 A1	06/93	EP			
	AK	85/04261	09/85	WO			
	AL						
	AM						
	AN						
	AO						
	AP						
	AQ						

OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)

	AT	
	AU	
	AV	
	AX	
	AY	

EXAMINER

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